2.7-V TO 5.5-V 12-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS

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- Four 12-Bit D/A Converters
- Programmable Settling Time of Either 3 µs or 9 μs Typ
- TMS320, (Q)SPI™, and Microwire™ Compatible Serial Interface
- **Internal Power-On Reset**
- **Low Power Consumption:** 8 mW, Slow Mode - 5-V Supply 3.6 mW, Slow Mode - 3-V Supply
- **Reference Input Buffer**
- **Voltage Output Range . . . 2× the Reference Input Voltage**
- **Monotonic Over Temperature**

description

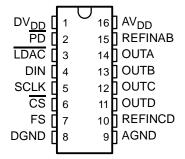
The TLV5614 is a quadruple 12-bit voltage output digital-to-analog converter (DAC) with a flexible 4-wire serial interface. The 4-wire serial interface allows glueless interface to TMS320, SPI, QSPI, and Microwire serial ports. The TLV5614 is programmed with a 16-bit serial word comprised of a DAC address, individual DAC control bits, and a 12-bit DAC value. The device has provision for two supplies: one digital supply for the serial interface (via pins DV_{DD} and DGND), and one for

- **Dual 2.7-V to 5.5-V Supply (Separate Digital** and Analog Supplies)
- Hardware Power Down (10 nA)
- Software Power Down (10 nA)
- Simultaneous Update

applications

- **Battery Powered Test Instruments**
- **Digital Offset and Gain Adjustment**
- **Industrial Process Controls**
- **Machine and Motion Control Devices**
- Communications
- **Arbitrary Waveform Generation**

D OR PW PACKAGE (TOP VIEW)



the DACs, reference buffers, and output buffers (via pins AV_{DD} and AGND). Each supply is independent of the other, and can be any value between 2.7 V and 5.5 V. The dual supplies allow a typical application where the DAC is controlled via a microprocessor operating on a 3 V supply (also used on pins DV_{DD} and DGND), with the DACs operating on a 5 V supply. Of course, the digital and analog supplies can be tied together.

The resistor string output voltage is buffered by a x2 gain rail-to-rail output buffer. The buffer features a Class AB output stage to improve stability and reduce settling time. A rail-to-rail output stage and a power-down mode makes it ideal for single voltage, battery based applications. The settling time of the DAC is programmable to allow the designer to optimize speed versus power dissipation. The settling time is chosen by the control bits within the 16-bit serial input string. A high-impedance buffer is integrated on the REFINAB and REFINCD terminals to reduce the need for a low source impedance drive to the terminal. REFINAB and REFINCD allow DACs A and B to have a different reference voltage then DACs C and D.

The TLV5614 is implemented with a CMOS process and is available in a 16-terminal SOIC package. The TLV5614C is characterized for operation from 0°C to 70°C. The TLV5614I is characterized for operation from -40°C to 85°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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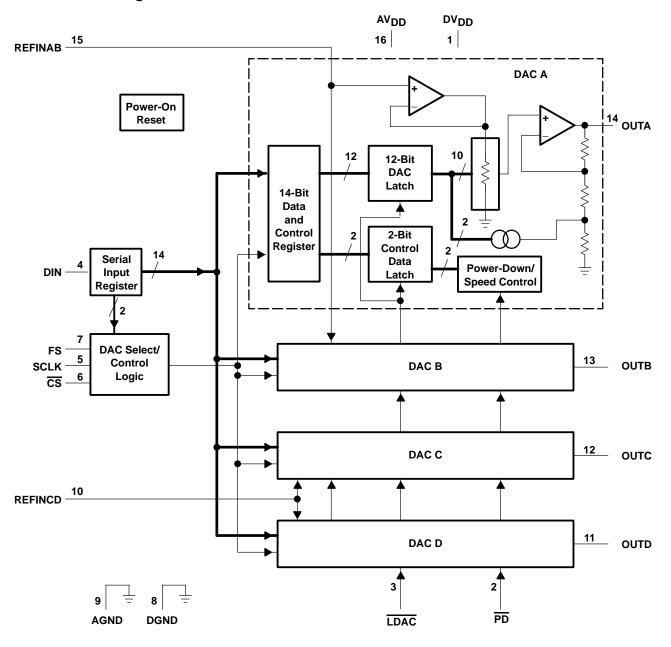


AVAILABLE OPTIONS

		PACKAGE	
TA	SOIC (D)	TSSOP (PW)	WSP [†] (YE)
0°C to 70°C	TLV5614CD	TLV5614CPW	
-40°C to 85°C	TLV5614ID	TLV5614IPW	TLV5614IYE

[†] Wafer Scale Packaging, also called Bumped Dice. See Figure 17.

functional block diagram





2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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Terminal Functions

TERMINAL I/O			PERCENTAGE
NAME	NO.	1/0	DESCRIPTION
AGND	9		Analog ground
AV_{DD}	16		Analog supply
CS	6	1	Chip select. This terminal is active low.
DGND	8		Digital ground
DIN	4	1	Serial data input
DV_{DD}	1		Digital supply
FS	7	I	Frame sync input. The falling edge of the frame sync pulse indicates the start of a serial data frame shifted out to the TLV5614.
PD	2	I	Power down pin. Powers down all DACs (overriding their individual power down settings), and all output stages. This terminal is active low.
LDAC	3	I	Load DAC. When the LDAC signal is high, no DAC output updates occur when the input digital data is read into the serial interface. The DAC outputs are only updated when LDAC is low.
REFINAB	15	I	Voltage reference input for DACs A and B.
REFINCD	10	I	Voltage reference input for DACs C and D.
SCLK	5	I	Serial clock input
OUTA	14	0	DACA output
OUTB	13	0	DACB output
OUTC	12	0	DACC output
OUTD	11	0	DACD output

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, (DV _{DD} , AV _{DD} to GND)	7 V
Supply voltage difference, (AV _{DD} to DV _{DD})	2.8 V to 2.8 V
Digital input voltage range	0.3 V to DV _{DD} + 0.3 V
Reference input voltage range	0.3 V to AV _{DD} + 0.3 V
Operating free-air temperature range, T _A : TLV5614C	0°C to 70°C
TLV5614I	–40°C to 85°C
Storage temperature range, T _{stg}	65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

TLV5614 2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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recommended operating conditions

		MIN	NOM	MAX	UNIT
County works are AV DV	5-V supply	4.5	5	5.5	
Supply voltage, AV _{DD} , DV _{DD}	3-V supply	2.7	3	3.3	V
I Park Javash diselect Second and to a very	DV _{DD} = 2.7 V	2			.,
High-level digital input voltage, V _{IH}	DV _{DD} = 5.5 V	2.4			V
Law law Later Construction V	DV _{DD} = 2.7 V			0.6	.,
Low-level digital input voltage, V _{IL}	DV _{DD} = 5.5 V			1	V
Defended by the DEFINAR DEFINIOR transition	5-V supply, See Note 1	0	2.048	V _{DD} -1.5	.,
Reference voltage, V _{ref} to REFINAB, REFINCD terminal	3-V supply, See Note 1	0	1.024	V _{DD} -1.5	V
Load resistance, R _L		2	10		kΩ
Load capacitance, CL				100	pF
Serial clock rate, SCLK				20	MHz
	TLV5614C	0		70	
Operating free-air temperature	TLV5614I	-40		85	ပ္

NOTE 1: Voltages greater than AVDD/2 cause output saturation for large DAC codes.

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

static DAC specifications

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
	Resolution			12			bits
	Integral nonlinearity (INL), end p	oint adjusted	See Note 2		±1.5	±4	LSB
	Differential nonlinearity (DNL)		See Note 3		±0.5	±1	LSB
EZS	Zero scale error (offset error at	zero scale)	See Note 4			±12	mV
	Zero scale error temperature co	efficient	See Note 5		10		ppm/°C
EG	Gain error		See Note 6			±0.6	% of FS voltage
	Gain error temperature coefficie	nt	See Note 7		10		ppm/°C
DODD	Decree and the second section	Zero scale	Con Nation Count C		-80		dB
PSRR	Power supply rejection ratio	Full scale	See Notes 8 and 9		-80		dB

- NOTES: 2. The relative accuracy or integral nonlinearity (INL) sometimes referred to as linearity error, is the maximum deviation of the output from the line between zero and full scale excluding the effects of zero code and full-scale errors.
 - 3. The differential nonlinearity (DNL) sometimes referred to as differential error, is the difference between the measured and ideal 1 LSB amplitude change of any two adjacent codes. Monotonic means the output voltage changes in the same direction (or remains constant) as a change in the digital input code.
 - 4. Zero-scale error is the deviation from zero voltage output when the digital input code is zero.

 - 5. Zero-scale-error temperature coefficient is given by: E_{ZS} TC = $[E_{ZS}$ (T_{max}) E_{ZS} (T_{min})]/ V_{ref} × 10⁶/(T_{max} T_{min}).

 6. Gain error is the deviation from the ideal output (2 V_{ref} 1 LSB) with an output load of 10 k Ω excluding the effects of the zero-error.
 - 7. Gain temperature coefficient is given by: $E_G TC = [E_G(T_{max}) E_G(T_{min})]/V_{ref} \times 10^6/(T_{max} T_{min})$.
 - 8. Zero-scale-error rejection ratio (EZS-RR) is measured by varying the AVDD from 5 ± 0.5 V and 3 ± 0.3 V dc, and measuring the proportion of this signal imposed on the zero-code output voltage.
 - Full-scale rejection ratio (EG-RR) is measured by varying the AVDD from 5 ± 0.5 V and 3 ± 0.3 V dc and measuring the proportion of this signal imposed on the full-scale output voltage after subtracting the zero scale change.



2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

individual DAC output specifications

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VO	Voltage output range	$R_L = 10 \text{ k}\Omega$			AV _{DD} -0.4	V
	Output load regulation accuracy	$R_L = 2 \text{ k}\Omega \text{ vs } 10 \text{ k}\Omega$		0.1	0.25	% of FS voltage

reference inputs (REFINAB, REFINCD)

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT	
٧ı	Input voltage range	See Note 10		0		AV _{DD} -1.5	V	
R _I	Input resistance				10		$M\Omega$	
Cl	C _I Input capacitance						pF	
	Reference feed through	REFIN = 1 V _{pp} at 1 kHz + 1.024 V dc (see Note 11)			-75		dB	
	Defense es innut han duidth	DEEIN 0.0 V . 4.004 V do lorge signal	Slow		0.5		N41.1-	
	Reference input bandwidth	REFIN = 0.2 V _{pp} + 1.024 V dc large signal			1		MHz	

NOTES: 10. Reference input voltages greater than $V_{DD}/2$ cause output saturation for large DAC codes.

digital inputs (DIN, CS, LDAC, PD)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
lіН	High-level digital input current	$V_I = V_{DD}$			±1	μΑ
IIL	Low-level digital input current	V _I = 0 V			±1	μΑ
Cl	Input capacitance			3		pF

power supply

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
		5-V supply,	Slow		1.6	2.4	
	David and the control of	No load, Clock running, All inputs 0 V or V _{DD}	Fast		3.8	5.6	mA
IDD	Power supply current	3-V supply,	Slow		1.2	1.8	
		No load, Clock running, All inputs 0 V or DV _{DD}	Fast		3.2	4.8	mA
	Power down supply current (see Figure 12)				10		nA



^{11.} Reference feedthrough is measured at the DAC output with an input code = 000 hex and a V_{ref} (REFINAB or REFINCD) input = 1.024 Vdc + 1 V_{pp} at 1 kHz.

TLV5614 2.7-V TO 5.5-V 12-BIT 3- μ S QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

analog output dynamic performance

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
0.0		$C_L = 100 \text{ pF}, R_L = 10 \text{ k}\Omega,$	Fast		5		V/μs
SR	Output slew rate	V _O = 10% to 90%, V _{ref} = 2.048 V, 1024 V	Slow		1		V/μs
	0	To ± 0.5 LSB, $C_{I} = 100$ pF,	Fast		3	5.5	
t _S	Output settling time	$R_L = 10 \text{ k}\Omega$, See Notes 12 and 14	Slow		9	20	μs
		To \pm 0.5 LSB, C _I = 100 pF,	Fast		1		
ts(c)	Output settling time, code to code	$R_L = 10 \text{ k}\Omega$, See Note 13	Slow		2		μs
	Glitch energy	Code transition from 7FF to 800			10		nV-sec
SNR	Signal-to-noise ratio	Sinewave generated by DAC,			74		
S/(N+D)	Signal to noise + distortion	Reference voltage = 1.024 at 3 V and 2 $f_S = 400 \text{ KSPS}$,		66			
THD	Total harmonic distortion	fOUT = 1.1 kHz sinewave,		-68		dB	
SFDR	Spurious free dynamic range	- C _L = 100 pF, $-$ R _L = 10 kΩ, BW = 20 kHz			70		

NOTES: 12. Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change ofFFF hex to 080 hex for 080 hex to FFF hex.



^{13.} Settling time is the time for the output signal to remain within ±0.5 LSB of the final measured value for a digital input code change of one count.

^{14.} Limits are ensured by design and characterization, but are not production tested.

electrical characteristics over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted) (continued)

digital input timing requirements

		MIN	NOM	MAX	UNIT
t _{su(CS-FS)}	Setup time, CS low before FS↓	10			ns
tsu(FS-CK)	Setup time, FS low before first negative SCLK edge	8			ns
tsu(C16–FS)	Setup time, sixteenth negative SCLK edge after FS low on which bit D0 is sampled before rising edge of FS	10			ns
tsu(C16–CS)	Setup time. The first positive SCLK edge after D0 is sampled before \overline{CS} rising edge. If FS is used instead of the SCLK positive edge to update the DAC, then the setup time is between the FS rising edge and \overline{CS} rising edge.	10			ns
t _{wH}	Pulse duration, SCLK high	25			ns
t _{wL}	Pulse duration, SCLK low	25			ns
t _{su(D)}	Setup time, data ready before SCLK falling edge	8			ns
t _{h(D)}	Hold time, data held valid after SCLK falling edge	5			ns
twH(FS)	Pulse duration, FS high	20			ns

PARAMETER MEASUREMENT INFORMATION

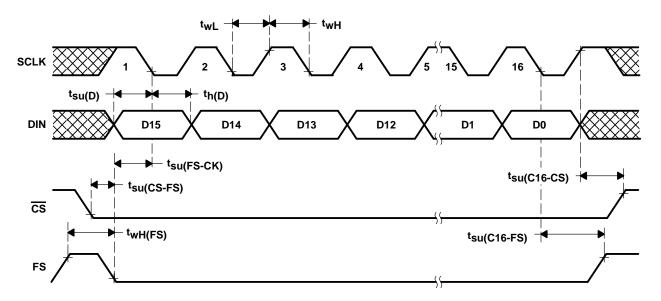


Figure 1. Timing Diagram

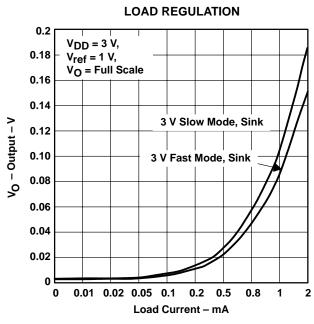
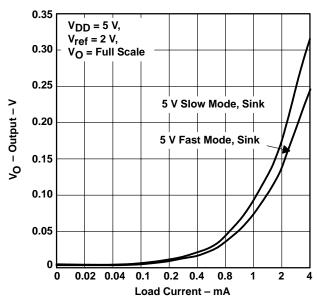


Figure 2



LOAD REGULATION

Figure 3

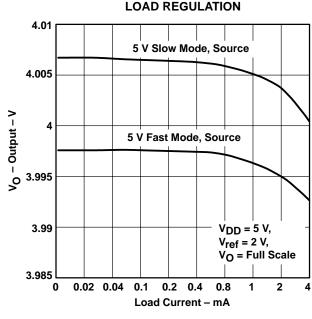


Figure 4

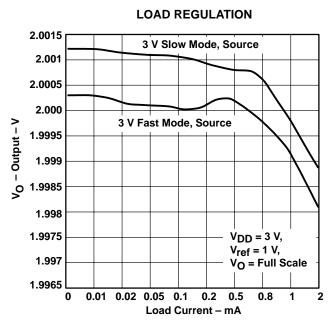
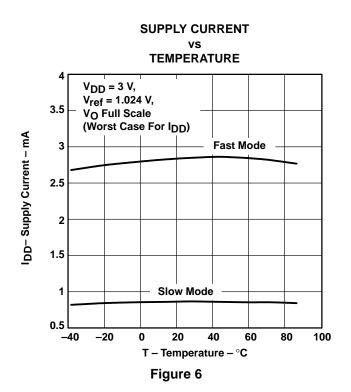
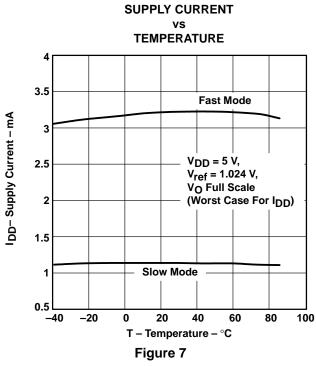
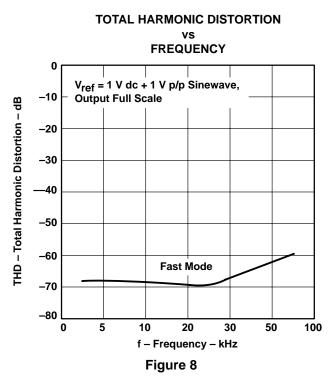


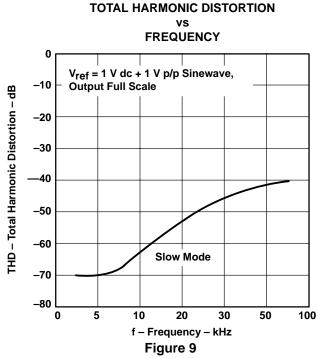
Figure 5





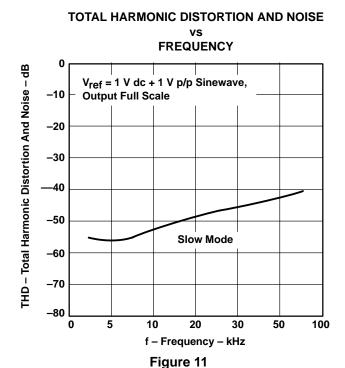






TOTAL HARMONIC DISTORTION AND NOISE **FREQUENCY** THD - Total Harmonic Distortion And Noise - dB $V_{ref} = 1 V dc + 1 V p/p Sinewave,$ Output Full Scale -10 -20 -30 -40 -50 **Fast Mode** -60 -70 -80 5 10 20 30 50 100 f - Frequency - kHz

Figure 10



SUPPLY CURRENT VS TIME (WHEN ENTERING POWER-DOWN MODE) 4000 3500 3000 2500 2000

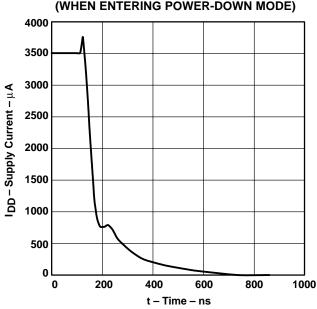


Figure 12



DIFFERENTIAL NONLINEARITY DNL - Differential Nonlinearity - LSB 0.3 $V_{CC} = 5 \text{ V}, V_{ref} = 2 \text{ V}, SCLK = 1 \text{ MHz}$ 0.25 0.2 0.15 0.1 0.05 0 -0.05 -0.1 -0.15 -0.2-0.25-0.3 0 256 768 1024 1280 1536 1792 2048 2304 2560 2816 3072 3328 3584 3840 4096 512 **Digital Code**

Figure 13

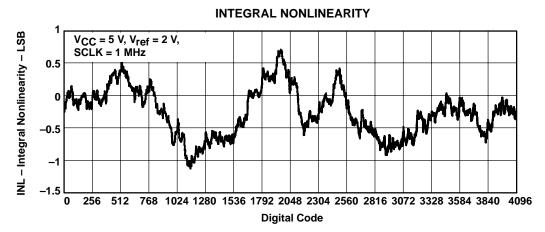


Figure 14



APPLICATION INFORMATION

general function

The TLV5614 is a 12-bit single supply DAC based on a resistor string architecture. The device consists of a serial interface, speed and power down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) is given by:

$$2 REF \frac{CODE}{2^n} [V]$$

where REF is the reference voltage and CODE is the digital input value within the range of 0_{10} to 2^n –1, where n=12 (bits). The 16-bit data word, consisting of control bits and the new DAC value, is illustrated in the *data* format section. A power-on reset initially resets the internal latches to a defined state (all bits zero).

serial interface

Explanation of data transfer: First, the device has to be enabled with \overline{CS} set to low. Then, a falling edge of FS starts shifting the data bit-per-bit (starting with the MSB) to the internal register on the falling edges of SCLK. After 16 bits have been transferred or FS rises, the content of the shift register is moved to the DAC latch which updates the voltage output to the new level.

The serial interface of the TLV5614 can be used in two basic modes:

- Four wire (with chip select)
- Three wire (without chip select)

Using chip select (four wire mode), it is possible to have more than one device connected to the serial port of the data source (DSP or microcontroller). The interface is compatible with the TMS320™ DSP family. Figure 15 shows an example with two TLV5614s connected directly to a TMS320 DSP.

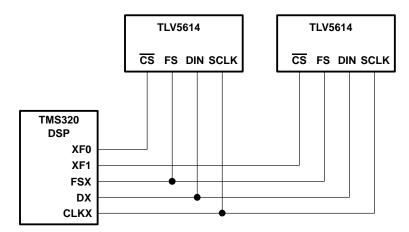


Figure 15. TMS320 Interface

TMS320 is a trademark of Texas Instruments.



I/O

SO

SK

TLV5614

FS

DIN

CS

SCLK

APPLICATION INFORMATION

serial interface (continued)

If there is no need to have more than one device on the serial bus, then \overline{CS} can be tied low. Figure 16 shows an example of how to connect the TLV5614 to a TMS320, SPI, or Microwire port using only three pins.

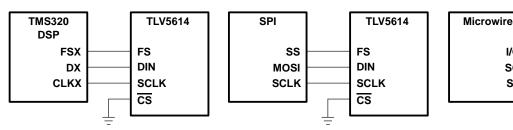


Figure 16. Three-Wire Interface

Notes on SPI and Microwire: Before the controller starts the data transfer, the software has to generate a falling edge on the I/O pin connected to FS. If the word width is 8 bits (SPI and Microwire), two write operations must be performed to program the TLV5614. After the write operation(s), the DAC output is updated automatically on the next positive clock edge following the sixteenth falling clock edge.

serial clock frequency and update rate

The maximum serial clock frequency is given by:

$$f_{SCLKmax} = \frac{1}{t_{wH(min)} + t_{wL(min)}} = 20 \text{ MHz}$$

The maximum update rate is:

$$f_{UPDATEmax} = \frac{1}{16\left(t_{wH(min)} + t_{wL(min)}\right)} = 1.25 \text{ MHz}$$

Note that the maximum update rate is a theoretical value for the serial interface since the settling time of the TLV5614 has to be considered also.

data format

The 16-bit data word for the TLV5614 consists of two parts:

Control bits (D15...D12) (D11 . . . D0) New DAC value

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
A1	A0	PWR	SPD		New DAC value (12 bits)										

X: don't care

SPD: Speed control bit. 1 → fast mode $0 \rightarrow \text{slow mode}$ PWR: Power control bit. $0 \rightarrow \text{normal operation}$ $1 \rightarrow power down$



APPLICATION INFORMATION

In power-down mode, all amplifiers within the TLV5614 are disabled. A particular DAC (A, B, C, D) of the TLV5614 is selected by A1 and A0 within the input word.

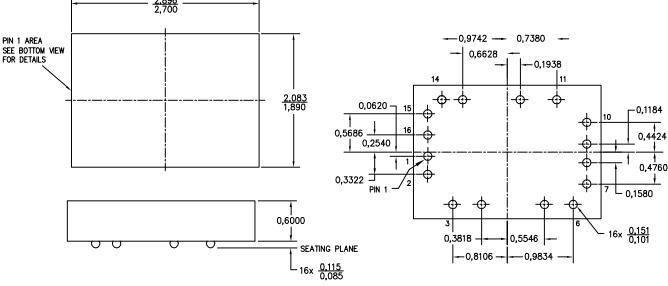
A1	A0	DAC
0	0	А
0	1	В
1	0	С
1	1	D

Using TLV5614IYE, Bumped Dice

- Melting point of eutectic solder is 183°C.
- Recommended peak reflow temperatures are in the 220°C to 230°C range.
- The use of underfill is required. The use of underfill greatly reduces the risk of thermal mismatch fails.

Underfill is an epoxy/adhesive that may be added during the board assembly process to improve board level/system level reliability. The process is to dispense the epoxy under the dice after die attach reflow. The epoxy adheres to the body of the device and to the printed-circuit board. It reduces stress placed upon the solder joints due to the thermal coefficient of expansion (TCE) mismatch between the board and the component. Underfill material is highly filled with silica or other fillers to increase an epoxy's modulus, reduce creep sensitivity, and decrease the material's TCE.

The recommendation for peak flow temperatures of 220°C to 230°C is based on general empirical results that indicate that this temperature range is needed to facilitate good wetting of the solder bump to the substrate or circuit board pad. Lower peak temperatures may cause nonwets (cold solder joints).



NOTE A: All linear dimensions are in millimeters.

NOTE B: This drawing is subject to change without notice.

NOTE C: Scale = 18x

Figure 17. TLV5614IYE Bumped Dice



TLV5614 interfaced to TMS320C203 DSP

hardware interfacing

Figure 17 shows an example of how to connect the TLV5614 to a TMS320C203 DSP. The serial port is configured in burst mode, with FSX generated by the TMS320C203 to provide the frame sync (FS) input to the TLV5614. Data is transmitted on the DX line, with the serial clock input on the CLKX line. The general-purpose input/output port bits IO0 and IO1 are used to generate the chip select (\overline{CS}) and DAC latch update (\overline{LDAC}) inputs to the TLV5614. The active low power down (\overline{PD}) is pulled high all the time to ensure the DACs are enabled.

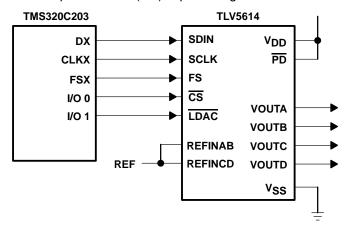


Figure 18. TLV5614 Interfaced With TMS320C203

software

The application example outputs a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal as the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses $\overline{\text{LDAC}}$ low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored in a look-up table, which describes two full periods of a sine wave.

The synchronous serial port of the DSP is used in burst mode. In this mode, the processor generates an FS pulse preceding the MSB of every data word. If multiple, contiguous words are transmitted, a violation of the tsu(C16–FS) timing requirement occurs. To avoid this, the program waits until the transmission of the previous word has been completed.



2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
; Processor: TMS320C203 runnning at 40 MHz
; Description:
; This program generates a differential in-phase (sine) on (OUTA-OUTB) and it's
; quadrature (cosine) as a differential signal on (OUTC-OUTD).
; The DAC codes for the signal samples are stored as a table of 64 12-bit values,
; describing 2 periods of a sine function. A rolling pointer is used to address the
; table location in the first period of this waveform, from which the DAC A samples
; are read. The samples for the other 3 DACs are read at an offset to this rolling
; pointer:
                     Offset from rolling pointer
  DAC
        Function
   Α
        sine
        inverse sine 16
   B
   C
        cosine
                     8
        inverse cosine24
; The on-chip timer is used to generate interrupts at a fixed rate. The interrupt
; service routine first pulses LDAC low to update all DACs simultaneously
; with the values which were written to them in the previous interrupt. Then all
; 4 DAC values are fetched and written out through the synchronous serial interface
; Finally, the rolling pointer is incremented to address the next sample, ready for
; the next interrupt.
; © 1998, Texas Instruments Inc.
;----- I/O and memory mapped regs ------
      .include "regs.asm"
;-----jump vectors ------
     .ps Oh
      b
           start
      b
            int1
         int23
timer_isr;
     b
     b
------ variables --------
temp .equ 0060h
r_ptr .equ 0061h
equ 0061h
iosr_stat .equ 0062h
DACa_ptr .equ 0063h
DACb_ptr .equ 0064h
        .equ 0065h
.equ 0066h
DACc_ptr
DACd_ptr
;-----constants-----
; DAC control bits to be OR'ed onto data
; all fast mode
DACa_control .equ 01000h
DACb_control .equ 05000h
DACc_control .equ 09000h
DACd_control .equ 0d000h
;----- tables -----
        02000h
  .ds
sinevals
  .word 00800h
   .word 0097Ch
   .word 00AE9h
   .word 00C3Ah
   .word 00D61h
   .word 00E53h
   .word 00F07h
   .word 00F76h
   .word 00F9Ch
   .word 00F76h
   .word 00F07h
   .word 00E53h
```



2.7-V TO 5.5-V 12-BIT 3-µS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN SLAS188B – SEPTEMBER 1998 – REVISED APRIL 2003

.word	00D61h 00C3Ah
.word	00C3AII
.word	0097Ch
.word	00800h
.word	00684h
.word	00517h 003C6h
.word .word	003C6H 0029Fh
.word	0025111 001ADh
.word	000F9h
.word	0008Ah
.word	00064h
.word	0008Ah 000F9h
.word .word	000F9H
.word	001ADH
.word	0029Fh 003C6h
.word	00517h
.word	00684h
.word	00800h
.word	0097Ch 00AE9h
.word	00AE3II
.word	00D61h
.word	00E53h
.word	00F07h
.word	00F76h
.word	00F9Ch 00F76h
.word .word	00F76H
.word	00E53h
.word	00D61h
.word	00C3Ah
.word	00AE9h
.word	0097Ch
.word	00800h
.word .word	00684h 00517h
.word	0031711 003C6h
.word	0029Fh
.word	001ADh
.word	000F9h
.word	0008Ah
.word	00064h 0008Ah
.word .word	0008An 000F9h
.word	000F9H
.word	0029Fh
.word	0029Fh 003C6h
.word	00517h
.word	00684h



2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
; Main Program
      .ps 1000h
      .entry
start
; disable interrupts
                    ; disable maskable interrupts
            INTM
      setc
      splk
            #Offffh, IFR; clear all interrupts
      splk #0004h, IMR; timer interrupts unmasked
; set up the timer
; timer period set by values in PRD and TDDR
; period = (CLKOUT1 period) x (1+PRD) x (1+TDDR)
  examples for TMS320C203 with 40MHz main clock
; Timer rate TDDR PRD; 80 kHz 9 24 (18h); 50 kHz 9 39 (27h)
;------
prd_val.equ 0018h
tcr_val.equ 0029h
tcr_val.equ 0029h
splk #0000h, temp; clear timer
      splk #prd_val, temp; set PRD
            temp, PRD
      splk #tcr_val, temp; set TDDR, and TRB=1 for auto-reload
      out temp, TCR
; Configure IOO/1 as outputs to be :
; IOO CS - and set high
; IO1 LDAC - and set high
            temp, ASPCR; configure as output
      in
      lacl temp
            #0003h
      or
      sacl temp
            temp, ASPCR
            temp, IOSR; set them high
      in
      lacl temp
            #0003h
      sacl temp
      out
           temp, IOSR
; set up serial port for
; SSPCR.TXM=1    Transmit mode - generate FSX
; SSPCR.MCM=1    Clock mode - internal clock source
; SSPCR.FSM=1 Burst mode
      splk #0000Eh, temp
           temp, SSPCR; reset transmitter
      splk #0002Eh, temp
      out
           temp,SSPCR
; reset the rolling pointer
      lacl #000h
      sacl r_ptr
; enable interrupts
     ;-----
; loop forever!
```



```
idle
                     ; wait for interrupt
next.
           next.
; all else fails stop here
done b done ; hang there
; Interrupt Service Routines
          ; do nothing and return
int1 ret
int23 ret
              ; do nothing and return
timer_isr:
       iosr_stat, IOSR; store IOSR value into variable space
  in
         lacl
        #0FFFDh
                    ; reset IO1 - LDAC low
  and
   sacl
        temp
         temp, IOSR
   out
         #0002h
                    ; set IO1 - LDAC high
  or
   sacl
         temp
   out
         temp, IOSR
   and
         #0FFFEh
                    ; reset IOO - CS low
   sacl temp
       temp, IOSR
   Out
   lacl
         r_ptr
                    ; load rolling pointer to accumulator
         #sinevals
   add
                    ; add pointer to table start
   sacl DACa_ptr
                   ; to get a pointer for next DAC a sample
   add
         #08h
                    ; add 8 to get to DAC C pointer
        DACc_ptr
   sacl
   add
         #08h
                    ; add 8 to get to DAC B pointer
   sacl
         DACb_ptr
   add
         #08h
                    ; add 8 to get to DAC D pointer
         DACd_ptr
   sacl
         *,ar0
                    ; set ar0 as current AR
  mar
   ; DAC A
   lar
         ar0, DACa_ptr; ar0 points to DAC a sample
                    ; get DAC a sample into accumulator
   lacl
         #DACa_control; OR in DAC A control bits
   or
   sacl
   out
         temp, SDTR
                   ; send data
        ______
; We must wait for transmission to complete before writing next word to the SDTR.;
TLV5614/04 interface does not allow the use of burst mode with the full packet; rate, as
we need a CLKX -ve edge to clock in last bit before FS goes high again,; to allow SPI
compatibility.
;-----
        rpt
  nop
   ; DAC B
         ar0, dacb_ptr; ar0 points to DAC a sample
   lar
                    ; get DAC a sample into accumulator
   lacl
         #DACb_control; OR in DAC B control bits
   or
   sacl
         temp
         temp, SDTR
   out
                    ; send data
                    ; wait long enough for this configuration
         #016h
  rpt
                    ; of MCLK/CLKOUT1 rate
  nop
; DAC C
   lar
         ar0, dacc_ptr; ar0 points to dac a sample
                   ; get DAC a sample into accumulator
   lacl
         #DACc_control; OR in DAC C control bits
   or
   sacl
            temp
            temp, SDTR; send data
   out
                   ; wait long enough for this configuration
   rpt
            #016h
                     ; of MCLK/CLKOUT1 rate
   nop
```

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```
; DAC D
   lar
             ar0, dacd_ptr; ar0 points to DAC a sample
          * ; get DAC a sample into accumulator #dacd_control; OR in DAC D control bits
   lacl
   or
   sacl
          temp
          temp, SDTR
                       ; send data
   out
                        ; load rolling pointer to accumulator
   lacl
          r_ptr
   add
          #1h
                        ; increment rolling pointer
                        ; count 0-31 then wrap back round
; store rolling pointer
          #001Fh
   and
   sacl
          r_ptr
                        ; wait long enough for this configuration
   rpt
          #016h
                         ; of MCLK/CLKOUT1 rate
   nop
; now take CS high again
   lacl iosr_stat ; load acc with iosr status
          #0001h
                         ; set IOO - CS high
          temp
   sacl
          temp, IOSR ;
   out
         intm ; re-enable interrupts ; return from interrupt
   clrc
   ret
.end
```



APPLICATION INFORMATION

TLV5614 interfaced to MCS®51 microcontroller

hardware interfacing

Figure 18 shows an example of how to connect the TLV5614 to an MCS $^{\circledR}$ 51 Microcontroller. The serial DAC input data and external control signals are sent via I/O Port 3 of the controller. The serial data is sent on the RxD line, with the serial clock output on the $\overline{\text{TxD}}$ line. Port 3 bits 3, 4, and 5 are configured as outputs to provide the DAC latch update ($\overline{\text{LDAC}}$), chip select ($\overline{\text{CS}}$) and frame sync (FS) signals for the TLV5614. The active low power down pin ($\overline{\text{PD}}$) of the TLV5614 is pulled high to ensure that the DACs are enabled.

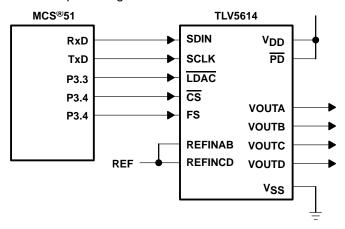


Figure 19. TLV5614 Interfaced With MCS[®]51

software

The example is the same as for the TMS320C203 in this data sheet, but adapted for a MCS[®]51 controller. It generates a differential in-phase (sine) signal between the VOUTA and VOUTB pins, and its quadrature (cosine) signal is the differential signal between VOUTC and VOUTD.

The on-chip timer is used to generate interrupts at a fixed frequency. The related interrupt service routine pulses $\overline{\text{LDAC}}$ low to update all 4 DACs simultaneously, then fetches and writes the next sample to all 4 DACs. The samples are stored as a look-up table, which describes one full period of a sine wave.

The serial port of the controller is used in Mode 0, which transmits 8 bits of data on RxD, accompanied by a synchronous clock on TxD. Two writes concatenated together are required to write a complete word to the TLV5614. The $\overline{\text{CS}}$ and FS signals are provided in the required fashion through control of IO port 3, which has bit addressable outputs.

```
; Processor: 80C51
; Description:
; This program generates a differential in-phase
(sine) on (OUTA-OUTB); and it's quadrature (cosine)
as a differential signal on (OUT\bar{C}-OUTD).
; © 1998, Texas Instruments Inc.
          -----
NAME GENIQ
MAIN SEGMENT
                  CODE
ISR
      SEGMENT
                  CODE
SINTBL SEGMENT
VAR1 SEGMENT
STACK SEGMENT
               DATA
IDATA
; Code start at address 0, jump to start
   CSEG AT 0
   LJMP start
                    ; Execution starts at address 0 on power-up.
;-----
; Code in the timerO interrupt vector
   CSEG AT OBH
                    ; Jump vector for timer 0 interrupt is 000Bh
       timer0isr
; Global variables need space allocated
          WAR1
   RSEG
temp_ptr: DS
rolling_ptr: DS
                 1
Interrupt service routine for timer 0 interrupts
   RSEG
timer0isr:
   PUSH
            PSW
   PUSH
            ACC
                     ; pulse LDAC low
   CLR
            TNT1
   SETB
                     ; to latch all 4 previous values at the same time
                     ; 1st thing done in timer isr => fixed period
   CLR
         тО
                      ; set CS low
   ; The signal to be output on each DAC is a sine function.
   ; One cycle of a sine wave is held in a table @ sinevals
   ; as 32 samples of msb, lsb pairs (64 bytes).
   ; We have ; one pointer which rolls round this table, rolling_ptr,
   ; incrementing by 2 bytes (1 sample) on each interrupt (at the end of
   ; this routine).
    The DAC samples are read at an offset to this rolling pointer:
   ; DAC Function Offset from rolling_ptr
     Α
         sine
   ;
     B
         inverse sine 32
         cosine
         inverse cosine48
   VOM
         DPTR, #sinevals; set DPTR to the start of the table
                      ; of sine signal values
         R7, rolling_ptr; R7 holds the pointer
   VOM
                     ; into the sine table
   VOM
                      ; get DAC A msb
                   ; msb of DAC A is in the ACC
   MOVC
        A,@A+DPTR
```



```
; transmit it - set FS low
   CLR
   MOV
         SBUF,A
                       ; send it out the serial port
   INC
                       ; increment the pointer in R7
                      ; to get the next byte from the table
   MOV
         A,R7
         A,@A+DPTR
   MOVC
                      ; which is the lsb of this sample, now in ACC
   A_MSB_TX:
   JNB
         TI,A_MSB_TX
                      ; wait for transmit to complete
   CLR
         TΙ
                      ; clear for new transmit
   MOV
         SBUF,A
                      ; and send out the 1sb of DAC A
   ; DAC C next
   ; DAC C codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives a cosine function
                  ; pointer in R7
         A,R7
         A,#0FH
   ADD
                      ; add 15 - already done one INC
                      ; wrap back round to 0 if > 64
   ANL
            A,#03FH
   MOV
         R7,A
                      ; pointer back in R7
        A,@A+DPTR
   MOVC
                      ; get DAC C msb from the table
   ORT
         A,#01H
                      ; set control bits to DAC C address
A LSB TX:
   JNB
         TI,A_LSB_TX ; wait for DAC A lsb transmit to complete
         T1
   SETB
                       ; toggle FS
   CLR T1
   CLR
         TТ
                       ; clear for new transmit
   MOV
         SBUF,A
                       ; and send out the msb of DAC C
                      ; increment the pointer in R7
   INC
         R7
   MOV
         A,R7
                      ; to get the next byte from the table
         A,@A+DPTR
                      ; which is the lsb of this sample, now in ACC
   MOVC
C_MSB_TX:
         TI,C_MSB_TX ; wait for transmit to complete
   JNB
   CLR
                      ; clear for new transmit
         TΙ
   MOV
         SBUF,A
                       ; and send out the 1sb of DAC C
   ; DAC B next
   ; DAC B codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives an inverted sine function
   VOM
         A,R7
                      ; pointer in R7
            A,#0FH
                      ; add 15 - already done one INC
   ADD
                      ; wrap back round to 0 if > 64
         A,#03FH
   ANT.
   MOV
         R7,A
                      ; pointer back in R7
   MOVC
        A,@A+DPTR
                      ; get DAC B msb from the table
   ORL
            A,#02H ; set control bits to DAC B address
C_LSB_TX:
   JNB
         TI,C_LSB_TX ; wait for DAC C lsb transmit to complete
   SETB
         T1
                       ; toggle FS
   CLR
         Т1
   CLR
         TТ
                       ; clear for new transmit
   MOV
         SBUF,A
                       ; and send out the msb of DAC B
   ; get DAC B LSB
   INC
         R7
                      ; increment the pointer in R7
         A,R7
   MOV
                      ; to get the next byte from the table
   MOVC
         A,@A+DPTR
                      ; which is the lsb of this sample, now in ACC
B_MSB_TX:
   JNB
         TI,B_MSB_TX
                      ; wait for transmit to complete
                       ; clear for new transmit
   CLR
         TΙ
   MOV
             SBUF,A
                      ; and send out the 1sb of DAC B
   ; DAC D codes should be taken from 16 bytes (8 samples) further on
   ; in the sine table - this gives an inverted cosine function
```



2.7-V TO 5.5-V 12-BIT 3-μS QUADRUPLE DIGITAL-TO-ANALOG CONVERTERS WITH POWER DOWN

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```
MOV
           A,R7
                         ; pointer in R7
          A,#0FH
                         ; add 15 - already done one INC
             A,#03FH; wrap back round to 0 if > 64
   ANL
         R7,A ; pointer back in R7
A,@A+DPTR ; get DAC D msb from the table
          R7,A
   VOM
   MOVC
                        ; set control bits to DAC D address
          A,#03H
   ORL
B LSB TX:
   JNB
           TI,B_LSB_TX ; wait for DAC B lsb transmit to complete
   SETB
           T1
                         ; toggle FS
           T1
   CLR
   CLR
           TI ; clear for new transmit
MOV SBUF, A
                        ; and send out the msb of DAC D
   TNC
                        ; increment the pointer in R7
          A,R7 ; to get the next byte from the table
A,@A+DPTR ; which is the lsb of this sample, now in ACC
   VOM
   MOVC
D_MSB_TX:
   JNB
           TI,D_MSB_TX ; wait for transmit to complete
                   ; clear for new transmit
   CLR
           TТ
   VOM
           SBUF,A
                         ; and send out the 1sb of DAC D
   ; increment the rolling pointer to point to the next sample
    ; ready for the next interrupt
          A,rolling_ptr
   VOM
                    ; add 2 to the rolling pointer
; wrap back round to 0 if > 64
          A,#02H
   ADD
   ANL
          A,#03FH
          rolling_ptr,A; store in memory again
   VOM
D_LSB_TX:
   JNB
           TI,D_LSB_TX ; wait for DAC D lsb transmit to complete
                         ; clear for next transmit
   CLR
           ΤI
                        ; FS high
   SETB
          T1
          T0
                         ; CS high
   SETB
   POP
           ACC
   POP
          PSW
   RETI
; Stack needs definition
   RSEG STACK
                         ; 16 Byte Stack!
; Main program code
   RSEG MAIN
start:
   MOV
          SP, #STACK-1 ; first set Stack Pointer
   CLR A
          SCON,A ; set serial port 0 to mode 0
TMOD,#02H ; set timer 0 to mode 2 - auto-reload
THO,#038H ; set THO for 5kHs interrupts
   VOM
   VOM
   MOV
                        ; set LDAC = 1
; set FS = 1
           INT1
   SETB
   SETB
           T1
                        ; set CS = 1
   SETB
                        ; enable timer 0 interrupts
; enable all interrupts
   SETB
          ETO
   SETB
   MOV
           rolling_ptr,A; set rolling pointer to 0
   SETB
         TR0
                        ; start timer 0
always:
   SJMP
          always
                         ; while(1) !
; Table of 32 sine wave samples used as DAC data
   RSEG SINTBL
```



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sineval	ls:
DW	01000H
DW	0903EH
DW	05097н
DW	0305CH
DW	0В086Н
DW	070CAH
DW	OF0E0H
DW	0F06EH
DW	0F039H
DW	0F06EH
DW	OF0E0H
DW	070CAH
DW	0В086Н
DW	0305CH
DW	05097H
DW	0903EH
DW	01000H
DW	06021H
DW	0A0E8H
DW	0C063H
DW	040F9H
DW	080B5H
DW	0009FH
DW	00051H
DW	00026H
DW	00051H
DW	0009FH
DW	080B5H
DW	040F9H
DW	0C063H
DW DW	0A0E8H 06021H
END	UUUZIH
עוונים	

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing		Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
							(6)				
TLV5614CD	ACTIVE	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	TLV5614C	Samples
TLV5614CPW	ACTIVE	TSSOP	PW	16	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	TV5614	Samples
TLV5614CPWG4	ACTIVE	TSSOP	PW	16	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	TV5614	Samples
TLV5614CPWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	0 to 70	TV5614	Samples
TLV5614ID	ACTIVE	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5614I	Samples
TLV5614IDR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5614I	Samples
TLV5614IPW	ACTIVE	TSSOP	PW	16	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5614	Samples
TLV5614IPWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5614	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

PACKAGE OPTION ADDENDUM

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(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF TLV5614:

● Enhanced Product: TLV5614-EP

NOTE: Qualified Version Definitions:

• Enhanced Product - Supports Defense, Aerospace and Medical Applications

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

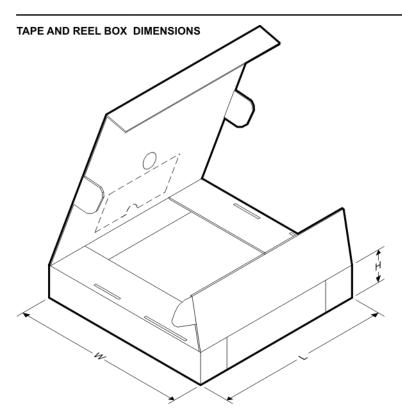
QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

All difficultions are florifinal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5614CPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TLV5614IDR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TLV5614IPWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

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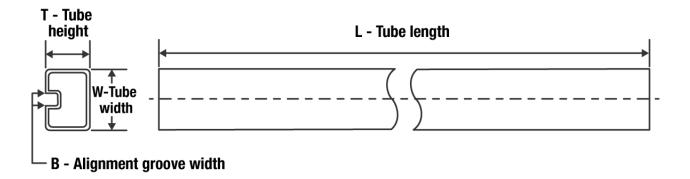
*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm) Width (mm)		Height (mm)
TLV5614CPWR	TSSOP	PW	16	2000	350.0	350.0	43.0
TLV5614IDR	SOIC	D	16	2500	350.0	350.0	43.0
TLV5614IPWR	TSSOP	PW	16	2000	350.0	350.0	43.0

PACKAGE MATERIALS INFORMATION

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TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TLV5614CD	D	SOIC	16	40	505.46	6.76	3810	4
TLV5614CPW	PW	TSSOP	16	90	530	10.2	3600	3.5
TLV5614CPWG4	PW	TSSOP	16	90	530	10.2	3600	3.5
TLV5614ID	D	SOIC	16	40	505.46	6.76	3810	4
TLV5614IPW	PW	TSSOP	16	90	530	10.2	3600	3.5

D (R-PDS0-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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